

# **GP2S40J0000F**

**Detecting Distance: 3mm Phototransistor Output, Compact Reflective Photointerrupter** 

## ■ Description

GP2S40J0000F is a compact-package, phototransistor output, reflective photointerrupter, with emitter and detector facing the same direction in a molding that provides non-contact sensing. The compact package series is a result of unique technology, combing transfer and injection molding, that also blocks visible light to minimize false detection.

This device has a long focal distance for this family of devices.

#### ■ Features

- 1. Reflective with Phototransistor Output
- 2. Highlights:
  - Compact Size
- 3. Key Parameters:
  - · Optimal Sensing Distance : 3mm
  - Package : 4×3×2.4mm
  - · Visible light cut resin to prevent
- 4. Lead free and RoHS directive compliant

#### ■ Agency approvals/Compliance

1. Compliant with RoHS directive

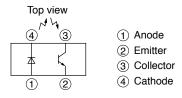
#### ■ Applications

- 1. Detection of object presence or motion.
- 2. Example: printer, optical storage

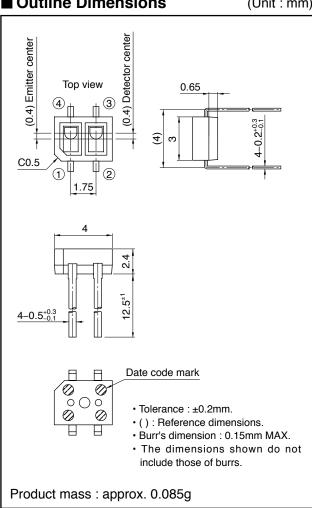
1



## ■ Internal Connection Diagram



#### **■** Outline Dimensions (Unit:mm)



Plating material : SnCu (Cu : TYP. 2%)



## Date code (Symbol)

January



July



February



August



March



September



April



October



May



November



June



December

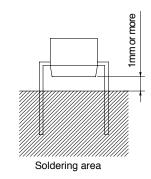


Country of origin

Japan



■ Absolute Maximum Ratings (T <sub>a</sub> =25°C)					
	Parameter	Symbol	Rating	Unit	
	Forward current	$I_F$	50	mA	
Input	Reverse voltage	$V_R$	6	V	
	Power dissipation	$P_{D}$	75	mW	
Output	Collector-emitter voltage	$V_{CEO}$	35	V	
	Emitter-collector voltage	V <sub>ECO</sub>	6	V	
	Collector current	$I_{\rm C}$	20	mA	
	Collector power dissipation	P <sub>C</sub>	75	mW	
Total j	power dissipation	P <sub>tot</sub>	100	mW	
Operating temperature		Topr	-25 to +85	°C	
Storage temperature		T <sub>stg</sub>	-40 to +100	°C	
*1Soldering temperature		T <sub>sol</sub>	260	°C	



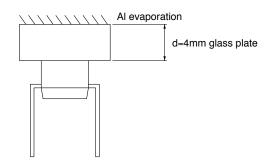
## **■** Electro-optical Characteristics

 $(T_a=25^{\circ}C)$ 

							,	
	Parameter		Symbol	Condition	MIN.	TYP.	MAX.	Unit
Lamust	Forward voltage		$V_{\rm F}$	I <sub>F</sub> =20mA	-	1.2	1.4	V
Input	Reverse current		$I_R$	V <sub>R</sub> =3V	_	_	10	μΑ
Output	Collector dark current		$I_{CEO}$	V <sub>CE</sub> =20V	_	1	100	nA
Tf	*2 Collector Current		$I_{C}$	$I_F=20\text{mA}, V_{CE}=5V$	0.5	_	3	mA
Transfer charac-	*3 Leak current		I <sub>LEAK</sub>	$I_F=20\text{mA}, V_{CE}=5V$	_	_	500	nA
teristics	Response time	Rise time	t <sub>r</sub>	V <sub>CE</sub> =2V, I <sub>C</sub> =100μA,	-	50	150	
		Fall time	$t_{\rm f}$	$R_{L}=1k\Omega$ , d=4mm	_	50	150	μs

<sup>\*2</sup> The condition and arrangement of the reflective object are shown below.
\*3 No reflective object

## ● Test Arrangement for Collector Current



<sup>\*1</sup> For 5s



Fig.1 Forward Current vs. Ambient Temperature

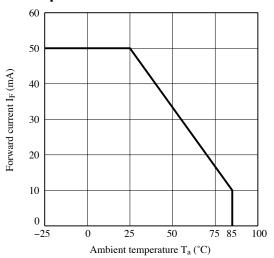


Fig.3 Forward Current vs. Forward Voltage

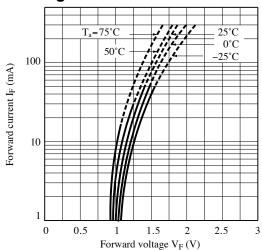


Fig.5 Collector Current vs.
Collector-Emitter Voltage

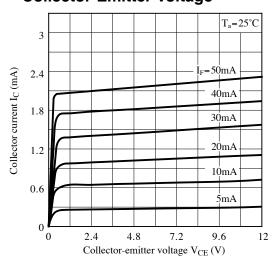


Fig.2 Collector Power Dissipation vs. Ambient Temperature

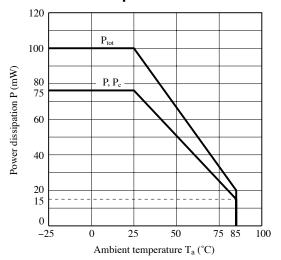


Fig.4 Collector Current vs. Forward Current

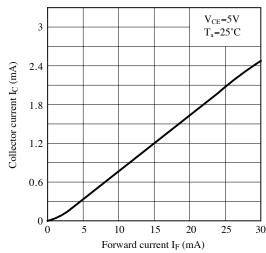


Fig.6 Relative Collector Current vs.
Ambient Temperature

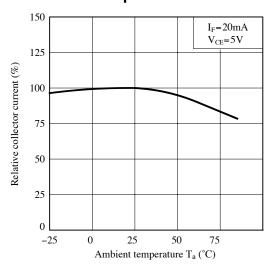




Fig.7 Collector Dark Current vs.
Ambient Temperature

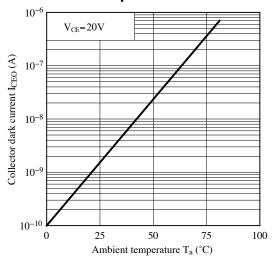


Fig.9 Test Circuit for Response Time

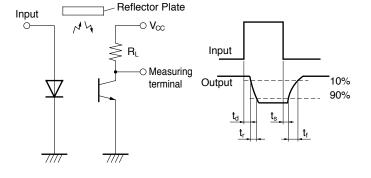


Fig.11 Detecting Position Characteristics (2)

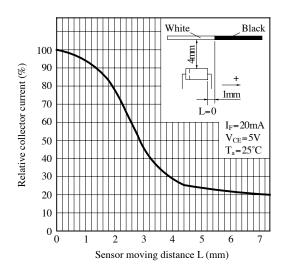


Fig.8 Response Time vs. Load Resistance

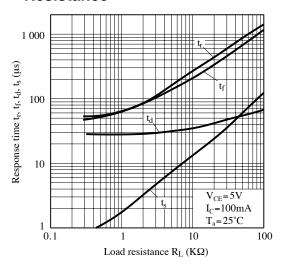


Fig.10 Detecting Position Characteristics (1)

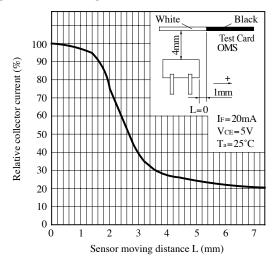
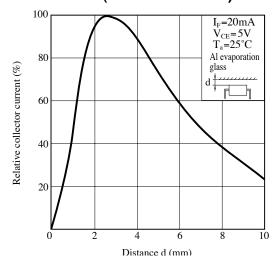


Fig.12 Relative Collector Current vs.
Distance (Reference value)



Remarks: Please be aware that all data in the graph are just for reference and not for guarantee.



### ■ Design Considerations

#### Design guide

1) Prevention of detection error

To prevent photointerrupter from faulty operation caused by external light, do not set the detecting face to the external light.

2) Distance characteristic

Please refer to Fig.12 (Relative collector current vs. Distance) to set the distance of the photointerrupter and the object.

This product is not designed against irradiation and incorporates non-coherent IRED.

#### Degradation

In the case of long term operation, please take the general IRED degradation (50% degradation over 5 years) into the design consideration.

#### Parts

This product is assembled using the below parts.

### • Photodetector (qty.: 1)

Category	Material	Maximum Sensitivity wavelength (nm)	Sensitivity wavelength (nm)	Response time (μs)
Phototransister	Silicon (Si)	930	700 to 1 200	20

### • Photo emitter (qty.: 1)

Category	Material	Maximum light emitting wavelength (nm)	I/O Frequency (MHz)
Infrared emitting diode (non-coherent)	Gallium arsenide (GaAs)	950	0.3

#### Material

Case	Lead frame	Lead frame plating	
Black polyphenylene sulfide resin	42Alloy	SnCu plating	



#### ■ Manufacturing Guidelines

#### Soldering Method

#### Flow Soldering:

Soldering should be completed below 260°C and within 5 s.

Soldering area is 1mm or more away from the bottom of housing.

Please take care not to let any external force exert on lead pins.

Please don't do soldering with preheating, and please don't do soldering by reflow.

#### Other notice

Please test the soldering method in actual condition and make sure the soldering works fine, since the impact on the junction between the device and PCB varies depending on the cooling and soldering conditions.

### Cleaning instructions

### Solvent cleaning:

Solvent temperature should be 45°C or below. Immersion time should be 3 minutes or less.

#### Ultrasonic cleaning:

Do not execute ultrasonic cleaning.

#### Recommended solvent materials:

Ethyl alcohol, Methyl alcohol and Isopropyl alcohol.

#### Presence of ODC

This product shall not contain the following materials.

And they are not used in the production process for this product.

Regulation substances: CFCs, Halon, Carbon tetrachloride, 1.1.1-Trichloroethane (Methylchloroform)

Specific brominated flame retardants such as the PBBOs and PBBs are not used in this product at all.

This product shall not contain the following materials banned in the RoHS Directive (2002/95/EC).

•Lead, Mercury, Cadmium, Hexavalent chromium, Polybrominated biphenyls (PBB), Polybrominated diphenyl ethers (PBDE).



### ■ Package specification

### ● Sleeve package

## Package materials

Sleeve : Polystyrene

Stopper: Styrene-Butadiene

### Package method

MAX. 50 pcs. of products shall be packaged in a sleeve. Both ends shall be closed by tabbed and tabless stoppers.

MAX. 20 sleeves in one case.



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